IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Leonard Forbes et al.

Examiner:

Theresa Doan

Serial No.:

09/883795

Group Art Unit: Docket:

303.355US4

2814

Filed: Title: June 18, 2001 DEAPROM AND TRANSISTOR WITH GALLIUM NITRIDE OR GALLIUM

ALUMINUM NITRIDE GATE

INFORMATION DISCLOSURE STATEMENT

Mail Stop RCE Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 et. seq., the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement.

Title: DEAPROM AND TRANSISTOR WITH GALLIUM NITRIDE OR GALLIUM ALUMINUM NITRIDE GATE

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

LEONARD FORBES ET AL.

By their Representatives,

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Date 29 AUGUST 2603 By
Robert E. Mates

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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Mail Stop RCE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 29th day of August, 2003.

Amy Moriarty

Signature of the signat

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary) 16F 8 7 2003 Sheet 18 10 ADE AND IN

Application Number	09/883795		
Filing Date	June 18, 2001		
First Named Inventor	Forbes, Leonard		
Group Art Unit	2814		
Examiner Name	Doan, Theresa		

Attorney	Docket	No:	303.355084

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EXAMINER

DATE CONSIDERED